

Final Product/Process Change Notification

Document # : FPCN21738X Issue Date: 12 May 2017

Title of Change:	Device Marking change and additional Test site for CAT5171TBI-50GT3		
Proposed first ship date:	4 September 2017		
Contact information:	Contact your local ON Semiconductor Sales Office or <shero.gao@onsemi.com></shero.gao@onsemi.com>		
Samples:	Contact your local ON Semiconductor Sales Office		
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <francis.lualhati@onsemi.com>.</francis.lualhati@onsemi.com>		
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <pcn.support@onsemi.com>.</pcn.support@onsemi.com>		
Change Part Identification:	Affected product from ON semiconductor with date code "HJ" representing WW36, 2017 and greater may be tested in UTAC Thai Limited or ON Leshan China and with the new marking style.		
Change category:	☐ Wafer Fab Change ☐ Assembly Change ☐ Test Change ☐ Other Marking & Test Site		
Change Sub-Category(s): Manufacturing Site Change/ Manufacturing Process Chan	Shipping/Packaging/Marking		
Sites Affected: All site(s) not ap	oplicable		

Description and Purpose:

This Product Change Notice is to notify customers of the change in product marking and of an additional test site (ON Semiconductor Leshan, LPS) for CAT5171TBI-50GT3.

As of September 4th, 2017 (WW36), ON will convert production to the new marking on parts tested at UTAC and LPS. Current marking will continue through September 4th, 2017 (WW36) and may be tested at either LPS or UTAC. Parts with the current date code are considered valid parts and will not be exchanged or recalled. The marking change is to match the ON standard marking as shown in the diagram below.

Under the current ON standard marking, there will no longer be bottom marking. Parts will continue to be tested to the same datasheet specifications at both locations, but may be tested on different test platforms.

	Before Change	After Change
Marking	Description	Description
Marking diagram	AFYM O 1	AFAYW Pb Free Package
Marking indication	AF = 50 kΩ Y = Production Year(Last Digit) M = Production Month (1 - 9, A, B, C)	AF = 50 kΩ A = Assembly Location YW = Production Year and Week

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Before		After (No Bottom Marking)	
UTAC Bottom Marking	After Top Marking	UTAC Top Marking	LPS Top Marking
6.102	AF54	AFGYW	AFGYW

Reliability Data Summary:

Not Applicable due to Change Category. Test Site Change is expected to have no impact to Reliability data.

Electrical Characteristic Summary:

Not Applicable due to Change Category. Test Site Change is expected to have no impact to Electrial Characteristics of the Products.

List of affected Standard Parts:

Part Number	Qualification Vehicle	
CAT5171TBI-50GT3	CAT5171TBI-50GT3	

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